# Study of Dielectric behavior of N-methylaniline-1,4-Dioxane mixture using Time Domain Reflectometry.

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**ABSTRACT:** The Complex permittivity spectra  $\varepsilon^*(\omega)=\varepsilon'$ -j $\varepsilon''$  of binary mixture of N-methylaniline with 1,4 Dioxane were obtained in the high frequency range 10 MHz to 30 GHz using Time Domain Reflectometry(TDR) technique. The static dielectric constant ( $\varepsilon_0$ ) and relaxation time ( $\tau$ ) have been obtained. On the basis of these parameters, intermolecular interaction and dynamics of the molecules at molecular level are studied.

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**Keywords:** Time domain, Complex dielectric spectra, Relaxation time.

#### I. INTRODUCTION:

Studying the dielectric properties at microwave frequency will reveal the dielectric relaxation of polar molecules and its variation with respect to the interaction with the neighbouring polar as well as non polar molecules. Patil et al. [1] obtained the complex dielectric spectra for alcohols and aniline binary mixtures and reported that  $\varepsilon_0$  and τ decrease with increasing concentration of aniline in the alcohol. From microwave absorption measurement in dilute solutions, Deogaonkar & coworkers [2] found that N, N-dimethylaniline form complexes with o-chlorophenol through hydrogen bonding at room temperature. Oswal et al [3] suggested strong cross association due to strong hydrogen bonding between -OH and -NH2 groups, from the viscosity and excess molar volume studies of liquid mixtures of alcohols with amine. In the present paper, the study of dielectric behaviour of N-methylaniline-1, 4 dioxane (NMA- DX) mixture in the frequency range of 10 MHz to 30 GHz using Time Domain Reflectometry (TDR) at temperature  $25^{0}$ C.

#### II. EXPERIMENTAL:

N-methyl aniline (NMA) and 1, 4-Dioxane (DX) was obtained commercially (S. D. Fine, India) and was used without further purification. The solutions were prepared. The complex dielectric spectra were obtained by the time domain reflectometry (TDR) technique. The Tektronix model no. DSA8200 Digital Serial

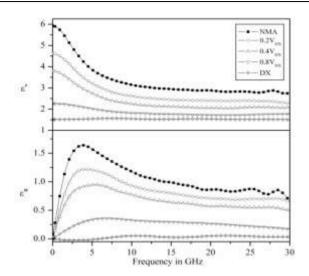
Analyzer sampling mainframe along with the sampling module 80E08 has been used for the time domain reflectometry (TDR). Reflected pulse without sample  $R_1$  (t) and with sample  $R_x$  (t) were recorded in time window of 2ns and digitized in 2000 points.

The time dependent data were processed to obtain complex reflection coefficient spectra  $\rho^*(\omega)$  over the frequency range from 10 MHz to 30 GHz as [4, 5].

$$\rho * (\omega) = \left(\frac{c}{j\omega d}\right) \left[\frac{p(\omega)}{q(\omega)}\right]$$

(1)

where  $p(\omega) \& q(\omega)$ are transforms of  $[R_1(t)-R_x(t)]$  and  $[R_1(t)+R_x(t)]$ respectively, c is the speed of light,  $\omega$  is the angular frequency, d is the effective pin length and j=  $\sqrt{-1}$ . The complex permittivity spectra  $\varepsilon^*(\omega)$  was obtained from reflection coefficient  $\rho^*(\omega)$  by applying calibration method as described earlier [6]. The dielectric permittivity  $\varepsilon'$  and dielectric loss ε" of NMA with1, 4 Dioxane at 25°C are shown in Figure. From dispersion plot it is observed that values of ε' decreases with increase in frequency and maximum of the dielectric loss  $\epsilon''_{max}$  shifts from the lower frequency to higher frequency in NMA-DX system.



#### III. RESULTS AND DISCUSSION:

The complex dielectric permittivity data were fitted to a Havriliak-Negami model using non linear least squares fit method in order to extract dielectric relaxation parameters with the following expression [7].

$$\varepsilon^*(\omega) = \varepsilon_{\infty} + \frac{\varepsilon_0 - \varepsilon_{\infty}}{\left[1 + (j\omega\tau)^{1-\alpha}\right]^{\beta}}$$
(2)

where  $\varepsilon^*(\omega)$  is complex permittivity at an angular frequency $\omega$ ,  $\varepsilon_0$  is the static permittivity,  $\varepsilon_{\infty}$ permittivity at high frequency,  $\tau$  is the relaxation time,  $\alpha$  is shape parameter representing symmetrical distribution of relaxation time and β shape parameter of an asymmetric relaxation curve. Equation (2) includes Cole-Cole ( $\beta$ =1) [8], Davidson-Cole ( $\alpha$ =0) [9], and Debve ( $\alpha$ =0,  $\beta$ =1) [10] relaxation models. The dielectric relaxation model for fitting dielectric parameters suitable for present systems is Davidson-Cole model. Therefore the complex permittivity spectra has been fitted in Davidson-Cole model with  $(\alpha=0)$  and  $\beta$   $(0 < \beta \le 1)$ as one of the fitting parameters along with  $\varepsilon_0$  & $\tau$ . The values of dielectric parameters  $\varepsilon_0$  and  $\tau$ obtained from equation (2) for NMA-DX with volume fraction of DX at 25°C are reported in table. The experimental values of  $\varepsilon_0$  and  $\tau$  are in good agreement reported earlier [11, 12]. It can be observed that  $\varepsilon_0$  decrease with increase in volume fraction of DX in NMA. Relaxation time (τ) decrease with increase in volume fraction of DX in NMA The decrease in τ values indicates that number of dipoles decreases in the solution, the intermediate structure formed rotates fast thereby giving the decrease in values of  $\tau$  in the solution.

Vol. Frac. of DX	$\epsilon_0$	τ
0.0	5.984(7)	39.26(15)
0.2	4.652(4)	35.17(10)
0.4	3.806(2)	33.08(8)
0.6	3.025(4)	28.25(8)
0.8	2.253(5)	20.42(26)
1.0	2.201(2)	7.2(20)

## IV. CONCLUSIONS:

The complex permittivity spectra of NMA with DX have been studied at  $25^{\circ}C$ , using time domain reflectometry technique in the frequency range 10 MHz to 30 GHz. The values of  $\epsilon_0$  shows systematic change with increase in volume fraction of DX in the system. The decrease in  $\tau$  values indicates that number of dipoles decreases in the solution, the intermediate structure formed rotates fast thereby giving the decrease in values of  $\tau$  in the solution.

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